

United States Patent and Trademark Office

UNITED STATES DEPARTMENT OF COMMERCE United States Patent and Trademark Office Address: COMMISSIONER OF PATENTS AND TRADEMARKS PO. Box 1450 Alexandria, Virginia 22313-1450 www.uspto.gov

APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.
09/915,325	07/27/2001	Mitsuru Hiura	862.C2315	5938
5514	7590 04/30/2003			
FITZPATRICK CELLA HARPER & SCINTO 30 ROCKEFELLER PLAZA			EXAMINER	
NEW YORK,			DUDDING, ALFRED E	
			ART UNIT	PAPER NUMBER
	•		2853	_
			DATE MAILED: 04/30/2003	6

Please find below and/or attached an Office communication concerning this application or proceeding.

		Application		
9	c)	Application No.	Applicant(s)	
4.	Office Action Summary	09/915,325	HIURA, MITSURU	
	omeen canmary	Examiner	Art Unit	
	The MAIL ING DATE of this communication on	Alfred E. Dudding	2853	
	• •			~
- Exter after - If the - If NO - Failur - Any r	ORTENED STATUTORY PERIOD FOR REPL MAILING DATE OF THIS COMMUNICATION. nsions of time may be available under the provisions of 37 CFR 1. SIX (6) MONTHS from the mailing date of this communication. period for reply specified above is less than thirty (30) days, a reply period for reply is specified above, the maximum statutory period re to reply within the set or extended period for reply will, by statution reply received by the Office later than three months after the mailined patent term adjustment. See 37 CFR 1.704(b).	136(a). In no event, however, ma ly within the statutory minimum of will apply and will expire SIX (6) i	y a reply be timely filed thirty (30) days will be considered timely. ### MONTHS from the mailing date of this communical	tion.
1) 🛛	Responsive to communication(s) filed on 27	luly 2001		
2a)□		is action is non-final.		
3)□	/			•
, —	Since this application is in condition for allow closed in accordance with the practice under on of Claims	Ex parte Quayle, 1935	natters, prosecution as to the merit C.D. 11, 453 O.G. 213.	s is
4) 🖾	Claim(s) 1-17 is/are pending in the application	l.		
	4a) Of the above claim(s) is/are withdra			
	Claim(s) is/are allowed.			
6)⊠	Claim(s) <u>1 and 10-17</u> is/are rejected.			
	Claim(s) <u>2-9</u> is/are objected to.			
8) [] (8	Claim(s) are subject to restriction and/o	r election requirement.		
Application	·		. *	
	he specification is objected to by the Examine			
10)🖂 1	the drawing(s) filed on <u>27 July 2001</u> is/are: a) ∑			
11)[□ T	Applicant may not request that any objection to the	drawing(s) be held in abo	eyance. See 37 CFR 1.85(a).	
,	he proposed drawing correction filed on	is: a) approved b)	disapproved by the Examiner.	
12)[□ T	If approved, corrected drawings are required in rep he oath or declaration is objected to by the Exa			
	nder 35 U.S.C. §§ 119 and 120	aminer.		
	Acknowledgment is made of a claim for foreign	priority under 35 U.S.C	. § 119(a)-(d) or (f).	
	All b) Some * c) None of: I. Certified copies of the priority documents			
	— and a september the priority documents		•	
	C. Certified copies of the priority documents C. Copies of the certified copies of the priori			
	B. Copies of the certified copies of the priori application from the International Burse the attached detailed Office action for a list of the attached detailed Detaile	eau (PCT Rule 17 2(a))	· -	
14)∏ Ac	knowledgment is made of a claim for domestic	priority under 35 U.S.C.	S 119(e) (to a provisional applicat	ion)
a) [oxdot The translation of the foreign language prov	isional application has	been received	1011).
15)∐ Ac	knowledgment is made of a claim for domestic	priority under 35 U.S.C	C. §§ 120 and/or 121.	
Attachment(s —	s)			
?) U Notice o	of References Cited (PTO-892) of Draftsperson's Patent Drawing Review (PTO-948) tion Disclosure Statement(s) (PTO-1449) Paper No(s) <u>3</u> .	4) Interview 5) Notice o 6) Other:	Summary (PTO-413) Paper No(s) f Informal Patent Application (PTO-152)	
Patent and Trade O-326 (Rev.	04.04)	on Summary	Part of Paner No	

Application/Control Number: 09/915,325

Art Unit: 2853

DETAILED ACTION

Claim Rejections - 35 USC § 101

1. 35 U.S.C. 101 reads as follows:

Whoever invents or discovers any new and useful process, machine, manufacture, or composition of matter, or any new and useful improvement thereof, may obtain a patent therefor, subject to the conditions and requirements of this title.

Claims 14, 15, and 17 are rejected under 35 U.S.C. 101 because the claimed invention is directed to non-statutory subject matter. Claims 14, 15, and 17 are directed to a factory which is considered a real estate term and is not patenable as such.

Claim Rejections - 35 USC § 102

2. The following is a quotation of the appropriate paragraphs of 35 U.S.C. 102 that form the basis for the rejections under this section made in this Office action:

A person shall be entitled to a patent unless -

- (a) the invention was known or used by others in this country, or patented or described in a printed publication in this or a foreign country, before the invention thereof by the applicant for a patent.
- 3. Claims 1, 10, and 11 are rejected under 35 U.S.C. 103(a) as being anticipated by Nishi et al. (U.S. 6,100,515 A).

Nishi et al. discloses a scanning exposure apparatus, and a semi-conductor device manufacturing method, Column 1, lines 19 – 25, and Figure 1, clearly seen, comprising a master stage for scanning a master, Figure 1, element 12; a substrate stage for scanning a substrate, Figure 1, element "WST", and positioning means for relatively positioning the substrate and the master, Figure 1, element 22B (drive unit for positioning substrate stage, element 22C, drive unit for positioning master stage).

'Application/Control Number: 09/915,325

Art Unit: 2853

Nishi et al. teaches the claimed inventions of a scanning velocity determination means for determining a scanning velocity so as to maximize the number of substrates that can be exposed per unit time and transfer means for supplying/recovering the substrate to/from said substrate stage, Column 4, lines 33 - 54.

4. Claims 12, 13, and 16 are rejected under 35 U.S.C. 103(a) as being unpatentable over Nishi et al. in view of Clarke et al. (U.S. 5,621,216 A).

Nishi et al. fail to teach the use of a local area network (LAN) connected to the semiconductor manufacturing device.

Clarke et al. discloses connecting a local area network to the manufacturing apparatuses; and the step of performing data communication of information about at least one of the manufacturing apparatuses between the local area network and an external network outside the semiconductor manufacturing apparatuses, Figure 1, element 11 ("PWS", personal work stations) and Column 3, lines 17-23.

It would have been obvious to one of ordinary skill in the art at the time the invention was made to use the LAN of Clarke et al. with the invention of Nishi et al. to quickly input different jobs and control manufacturing operations. The motivation/suggestion to do so is given by the '216 patent, Column 3, lines 15 –17, a personal computer (PC) that synchronizes the writing of the mask and the running of calibration and diagnostic programs.

Page 4

Application/Control Number: 09/915,325

Art Unit: 2853

Allowable Subject Matter

- 5. Claims 2-9 are objected to as being dependent upon a rejected base claim, but would be allowable if rewritten in independent form including all of the limitations of the base claim and any intervening claims.
- a. A search of prior art did not cite an apparatus wherein a scanning velocity determined from an exposure illuminance and a required exposure amount: Vd, and a scanning velocity at which the number of substrates that can be processed per unit time is maximized, which is determined from the transfer pattern size, a layout of the transfer pattern on the substrate, said transfer means, said master scanning means, said substrate stage scanning means, and said positioning means Vt as claimed in the limitations of claims 2 and 5-9.
- b. A search of prior art did not cite an apparatus wherein a lowest one of a maximum scanning velocity determined from apparatus performance: Vmax, a scanning velocity determined from an exposure illuminance and a required exposure amount: Vd, scanning velocity determined from the minimum number of pulses which is required for integration to ensure a uniform exposure amount: Vp, and scanning velocity at which the number of substrates that can be processed per unit time is maximized, which is determined from the transfer pattern size, a layout of the transfer pattern on the substrate, said transfer means, said master scanning means, said substrate stage scanning means, and said positioning means Vt as claimed in the limitations of claims 3 and 4.

Application/Control Number: 09/915,325

Art Unit: 2853

Conclusion

Any inquiry concerning this communication or earlier communications from the 6. examiner should be directed to Alfred Dudding whose telephone number is (703) 308-6082. The examiner can normally be reached on Monday-Friday from 8:30 AM to 3:00 PM. If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Russell Adams, AU 2853, can be reached at (703) 308-2847. The fax phone numbers for this Group are (703) 305-3432, (703) 305-3431, (703) 308-7382, (703) 308-7724, and (703) 308-7722.

Any inquiry of a general nature or relating to the status of this application or proceeding should be directed to the group receptionist whose telephone number is (703) 308-0956.

Alfred Dudding

4-25-17

Page 5